<u>PCN</u> N	Number:	20160	11900	04		PCN D	ate:	2/5/2016	
Title:	Datasheet f	or bq2426	6						
Custo	tomer Contact: PCN Manager		nager	1		ept: Qua		lity Services	
Chang	ge Type:					-		· ·	
	Assembly Site			Design		Wafe	r Bum	p Site	
	Assembly Process			Data Sheet			Wafer Bump Material		
	Assembly Materials			Part number change		Wafe	Wafer Bump Process		
	Mechanical Specification			Test Site		Wafe	Wafer Fab Site		
	Packing/Shipping/Labeling			Test Process		Wafe	Wafer Fab Materials		
						Wafe	r Fab I	Process	
			No	tification Details					
)escr	ription of Change	e:							
exas	Instruments Inco	rporated is	s annou	uncing an information of	only noti	fication	etc.		
-	Ilowing change hi Texas Instruments	- ,						bq24266	
				SLU	SBY5G – JUNE	E 2014-REVIS	ED DECE	MBER 2015	
	ges from Revision F (Au nanged absolute maximu			n G d I/O pins from 5.0 V to 5.5 V				Page 6	
<ul> <li>Ch</li> <li>Ad</li> <li>Ch</li> </ul>	hanged absolute maximulided $V_{IN} > V_{UVLO}$ test containinged image object for F	m value for SY dition for V <sub>BATU</sub> Figure 26	/S, TS and	d I/O pins from 5.0 ∨ to 5.5 ∨					
Ch     Ad     Ch Change	hanged absolute maximul Ided $V_{IN} > V_{UVLO}$ test containing the set of	n value for SY dition for V <sub>BATU</sub> Figure 26 cember 2014	(S, TS and JVLO· ) to Revis	d I/O pins from 5.0 ∨ to 5.5 ∨ ion F					
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Change Change Del Cha	hanged absolute maximul Ided $V_{IN} > V_{UVLO}$ test com- hanged image object for f es from Revision E (De leted devices bq24265 ar anged bq2426x To: bq24	m value for SY dition for V <sub>BATU</sub> Figure 26 cember 2014) nd bq24267 266 throughou	(S, TS and JVLO: ) to Revis	d I/O pins from 5.0 V to 5.5 V ion F					
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Ch     Ad     Ch     Chang     Del     Cha     Del     Del     Del     Del     Del     Del     Del	hanged absolute maximul Ided $V_{IN} > V_{UVLO}$ test com- hanged image object for f es from Revision E (De leted devices bq24265 ar anged bq2426x To: bq24 leted Features: Host-com- leted Features: Voltage-b anged text in the Descrip	m value for SY dition for V <sub>BATU</sub> Figure 26 cember 2014) ad bq24267 266 throughou rolled JEITA ( ased, JEITA ( tion From: "Th	(S, TS and VLO ) to Revis ut the data Compatible Compatible ne bq2426	d I/O pins from 5.0 V to 5.5 V ion F asheet	55) 66) To: "The b				
Ch     Ad     Change     Del     Cha     Del     Del     Del     Del     Del     Cha     Cha	hanged absolute maximul lded $V_{IN} > V_{UVLO}$ test com- hanged image object for f es from Revision E (De leted devices bq24265 ar anged bq2426x To: bq24 leted Features: Host-com- leted Features: Voltage-b anged text in the Descrip anged 1µF to 2.2µF on th	m value for SY dition for V <sub>BATU</sub> Figure 26 cember 2014 d bq24267 266 throughou rolled JEITA ( ased, JEITA ( tion From: "Th e DRV pin of	(S, TS and VLO ) to Revis ut the data Compatible Compatible the bq2426 the Applic	d I/O pins from 5.0 V to 5.5 V ion F asheet e NTC Monitoring Input (bq2426 e NTC Monitoring Input (bq2426 5, bq24266, and bq24267 are'	65) 66) To: "The b				
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Change     Change     Del     Cha     Del     Cha     Del     Cha     Del     Cha     Del     Cha     Del     Cha     Cha     Cha     Del     Cha     Cha     Del     Cha     Del     Cha     Del     Cha     Del     Cha     Del     Cha     Del	hanged absolute maximul lded $V_{IN} > V_{UVLO}$ test com- hanged image object for f es from Revision E (De leted devices bq24265 ar anged bq2426x To: bq24 leted Features: Voltage-b anged text in the Descrip anged 1µF to 2.2µF on the leted the <i>Device Compar</i> leted the bq24265 pinout anged the DRV pin descrip- he <i>Pin Functions</i> table anged absolute maximum ved the Stroage temperar anged the <i>Handling Ratir</i> leted references to BQ24	m value for SY dition for V <sub>BATU</sub> Figure 26 cember 2014) ad bq24267 266 throughou rolled JEITA ( ased, JEITA ( tion From: "Th te DRV pin of <i>son Table</i> intion From: " value for DR ture to <i>Absolu</i> gs table To: E 265 and BQ24	(S, TS and VLO ) to Revis ut the data Compatible Compatible the bq2426 the Applic 1μF of cer V pin from te Maximu SD Rating 4266 in V <sub>E</sub>	d I/O pins from 5.0 V to 5.5 V ion F asheet	55) 56) " To: "The b ", 10V, X5R "ristics	oq24266 is.	." apacitor	6 	
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<ul> <li>Chang</li> <li>Chang</li> <li>Chang</li> <li>Cha</li> <li>Del</li> <li>Cha</li> <li>ant to the set of the</li></ul>	anged absolute maximul lded $V_{IN} > V_{UVLO}$ test com- nanged image object for f es from Revision E (De leted devices bq24265 ar anged bq2426x To: bq24 leted Features: Host-com- leted Features: Host-com- leted Features: Voltage-b anged text in the Descrip anged 1µF to 2.2µF on th leted the <i>Device Compar-</i> leted references to BQ24 leted references to BQ24 leted text from the <i>Overv-</i> arge current and voltage opport only."	m value for SY dition for V <sub>BATU</sub> Figure 26 cember 2014) ad bq24267 266 throughou rolled JEITA C ased, JEITA C tion From: "Th the DRV pin of son Table in value for DR ture to Absolu gs table To: E 265 and BQ24 ew section: "T using the CE1	(S, TS and VLO ) to Revis ut the data Compatible Compatible the bq2426 the Applic 1μF of cer V pin from the Maximu SD Rating 4266 in K <sub>R</sub> The bq242 and CE2	d I/O pins from 5.0 V to 5.5 V ion F asheet e NTC Monitoring Input (bq2426 e NTC Monitoring Input (bq2426 5, bq24266, and bq24267 are' cation Schematic cation Schematic main capacitance" To: "a 2.2uF n 5.0 V to 5.5 V. um Ratings <sup>(1)</sup> gs table <sub>SATREG</sub> of the Electrical Character set of the Electrical Character fo allows a host to monitor a N	55) 56) 70: "The b 7, 10V, X5R 7, 10V, X5R 70: TC thermis res a TS inp	oq24266 is. or better c tor and adj but with HC	apacitor ust the T/COLD	6 	

Changed the External NTC Monitoring (CE1, CE2, and TS) section To: External NTC Monitoring (TS)	21							
<ul> <li>Deleted Table "CE1, CE2 Configurations"</li> </ul>								
<ul> <li>Deleted text from the <i>Application Information</i> section: "but can be used to evaluate the bq24265 or bq24267 as well. To configure the board to use the bq24265, the /CE1 and /CE2 pins are used to comply with JEITA per Table 2</li></ul>								
The datasheet number will be changing.								
Device Family Change From: Change To:								
bq24266 SLUSBY5E SLUSBY5G								
http://www.ti.com/product/bq24266 Reason for Change:								
To more accurately reflect device characteristics.								
Anticipated impact on Fit, Form, Function, Quality or Reliability (positive / negative)	(ive):							
No anticipated impact. This is a specification change announcement only. There are no ch the actual device.	anges to							
Changes to product identification resulting from this PCN:								
None.								
Product Affected:								

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